

FIG. 1

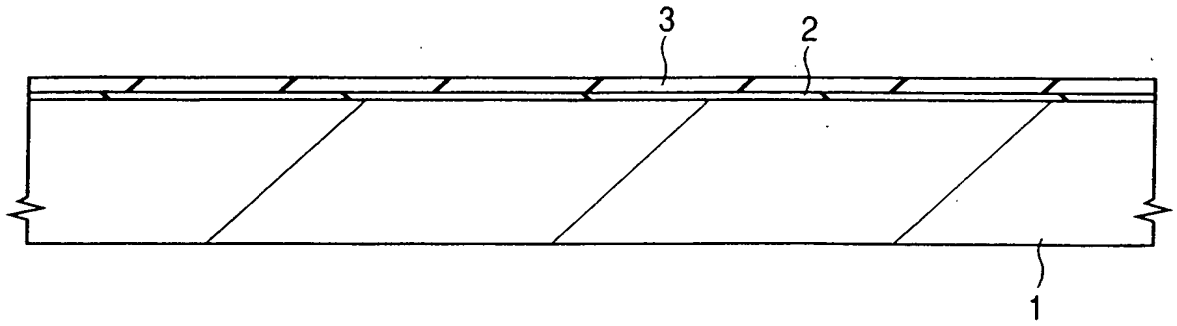


FIG. 2

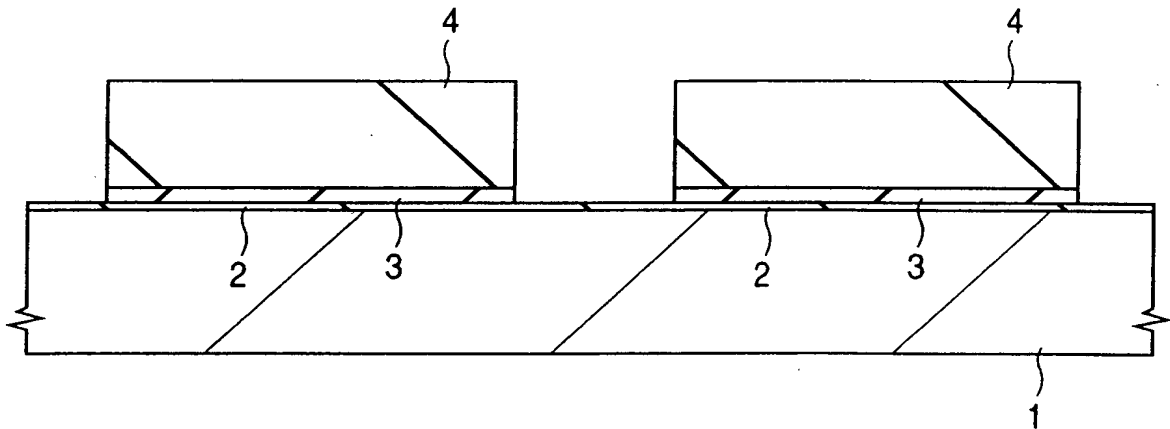


FIG. 3

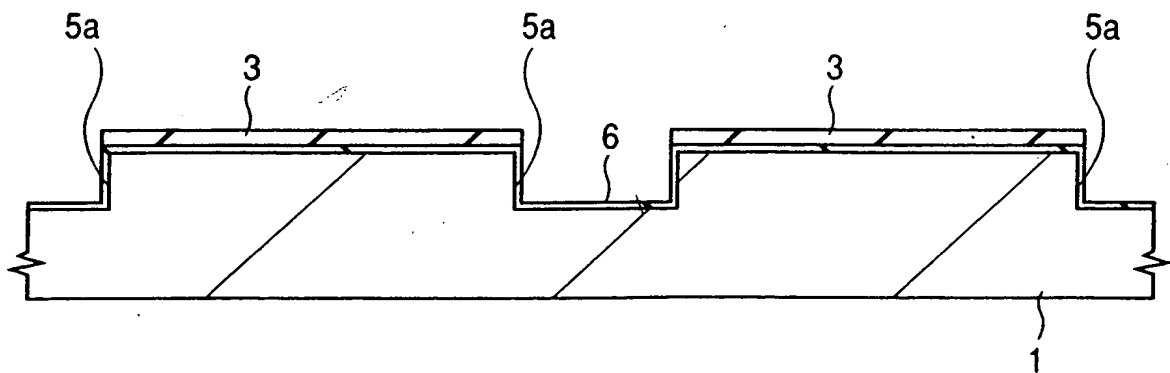


FIG. 4

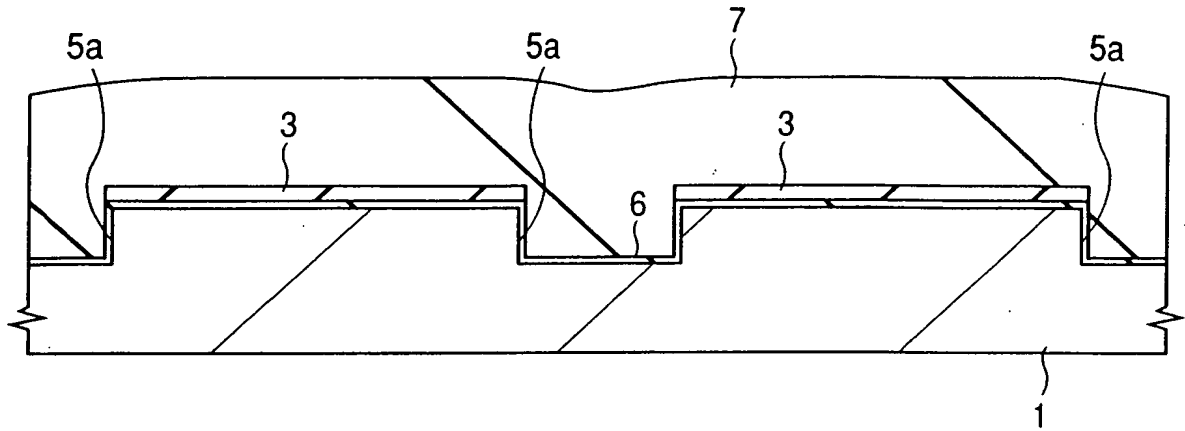


FIG. 5

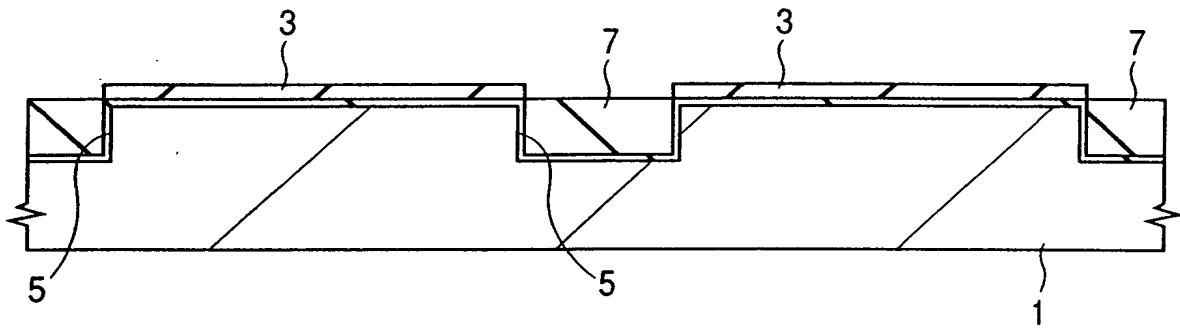


FIG. 6

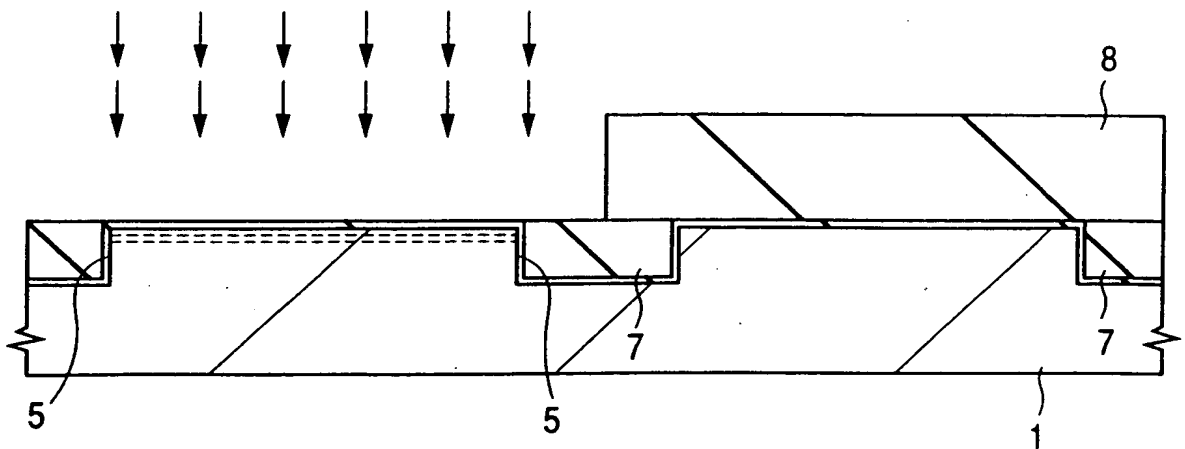


FIG. 7

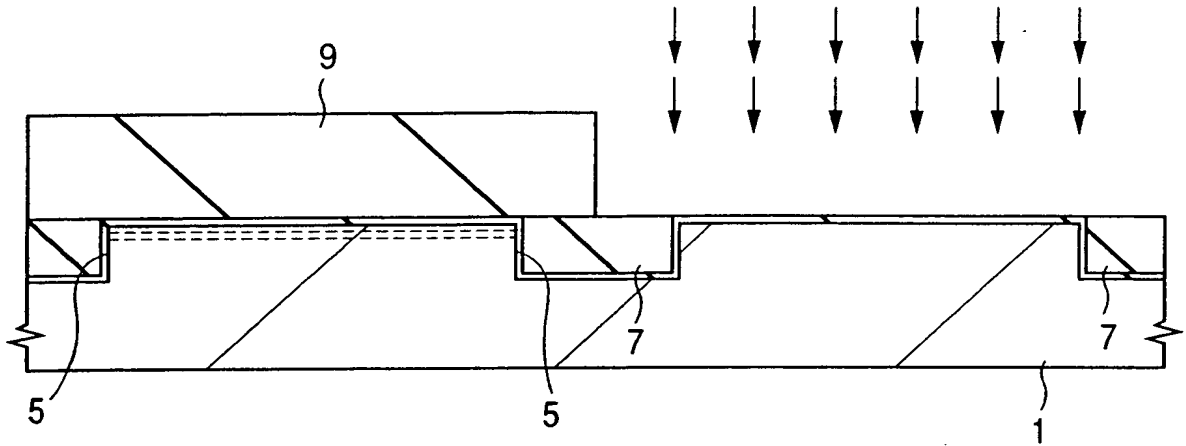


FIG. 8

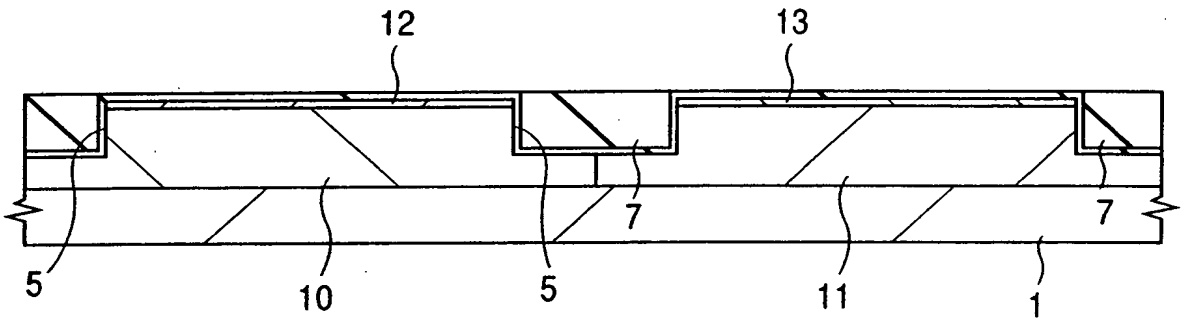


FIG. 10

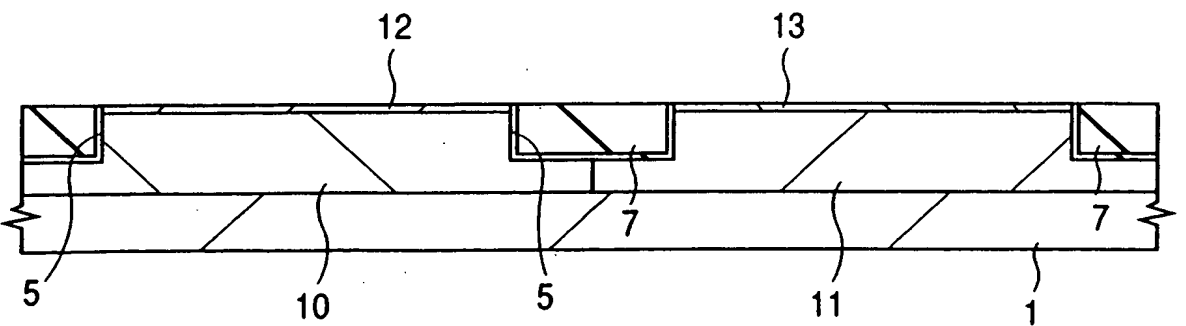


FIG. 9

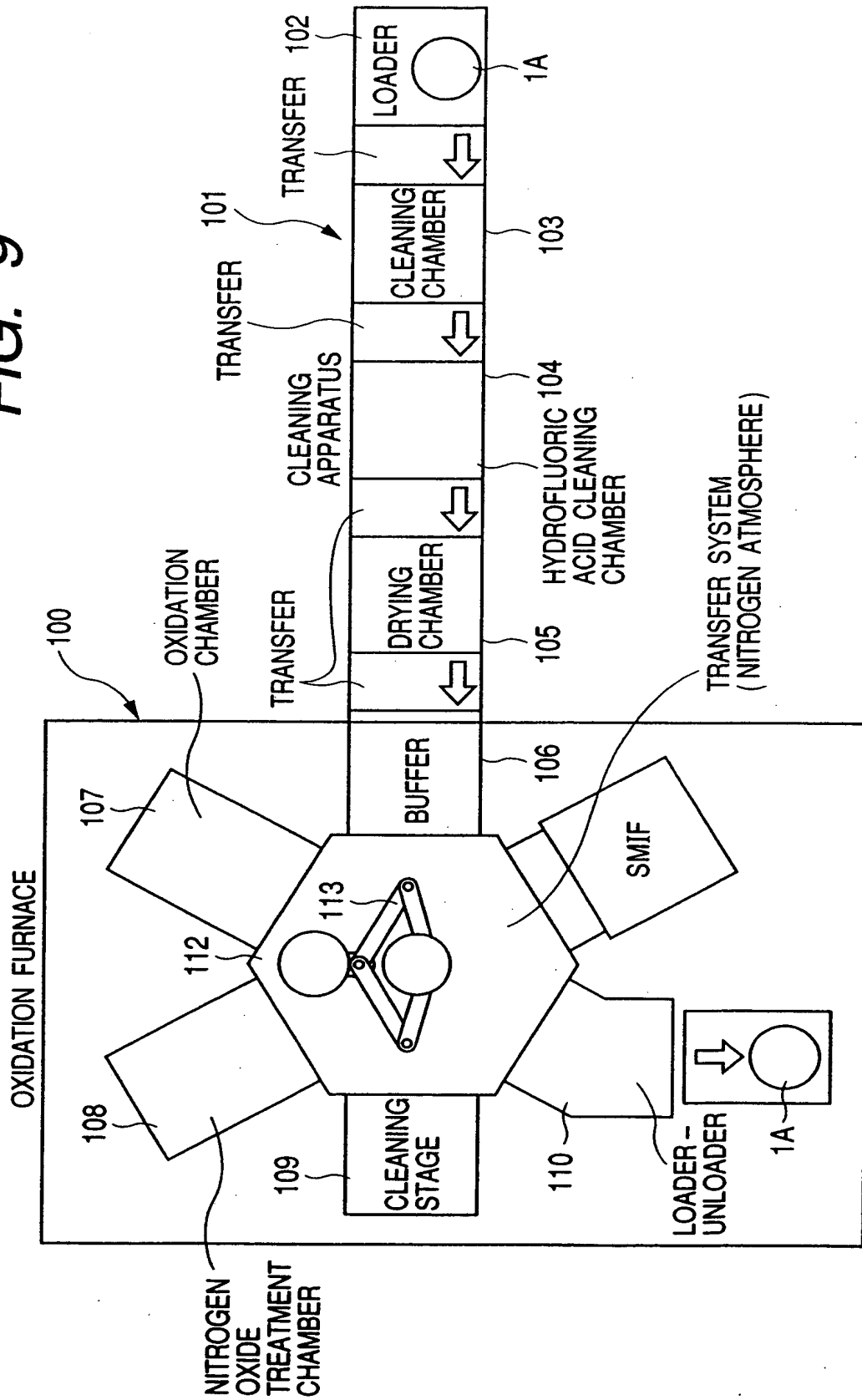


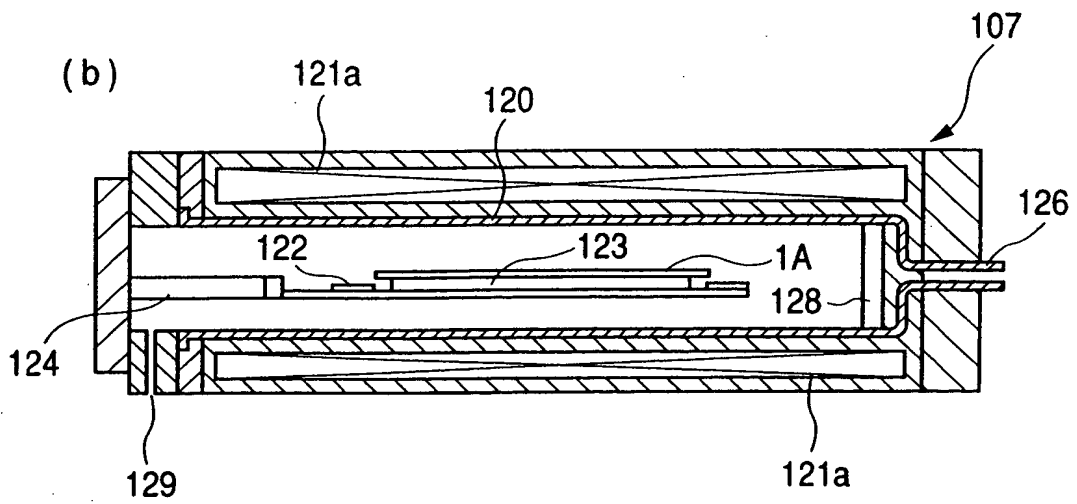
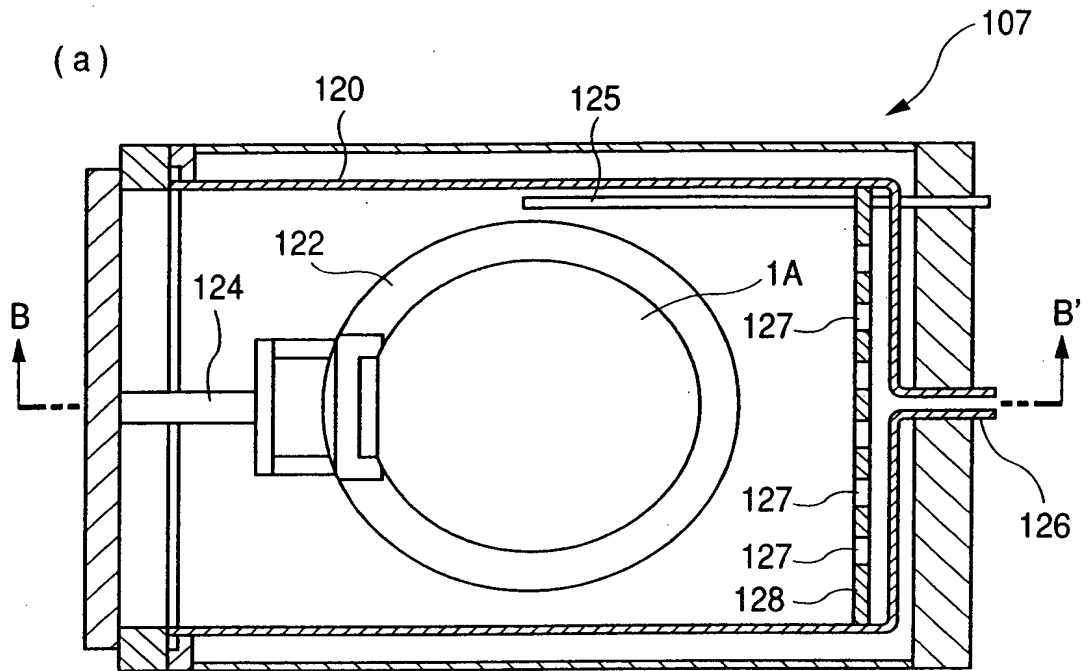
FIG. 11

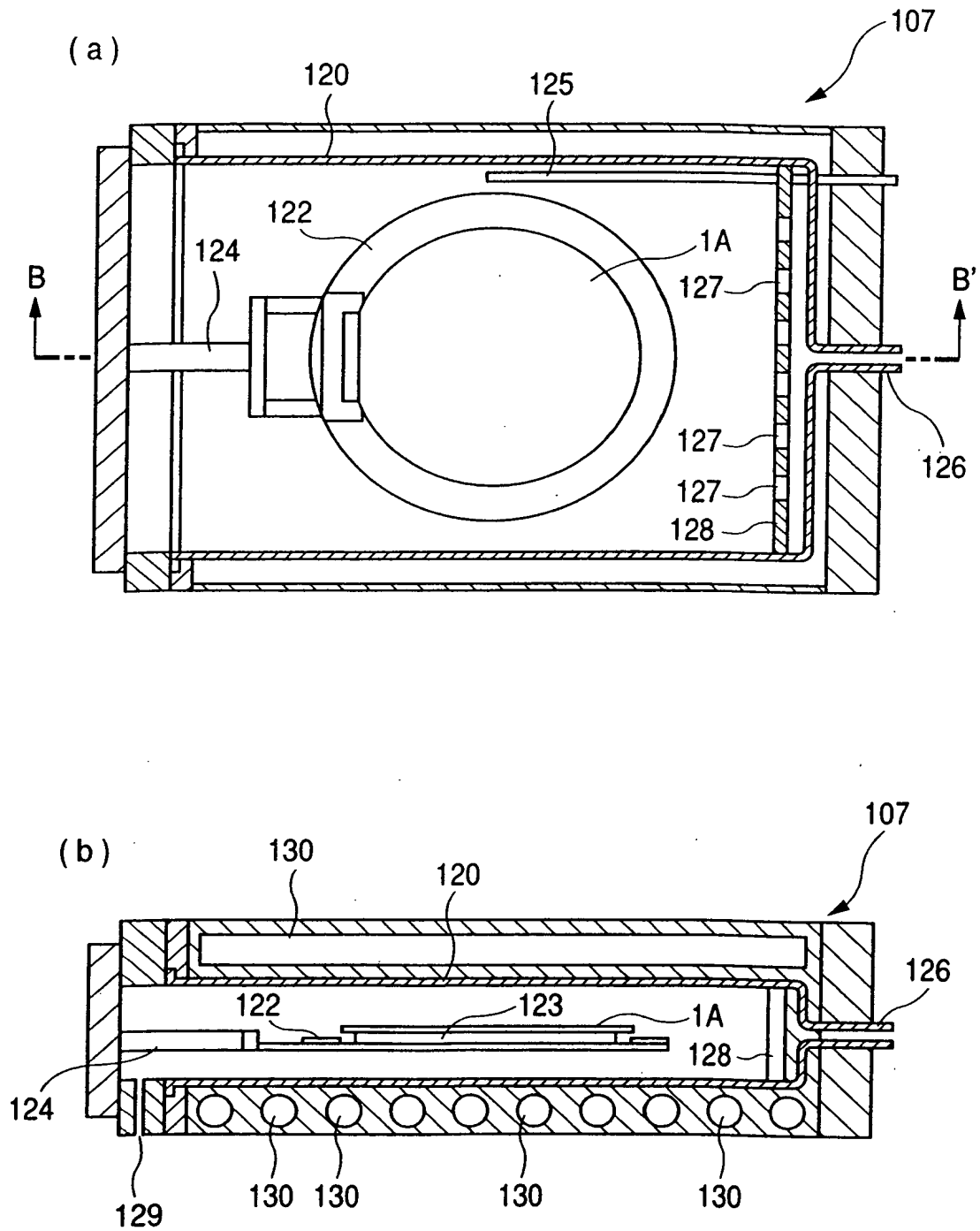
FIG. 12

FIG. 13

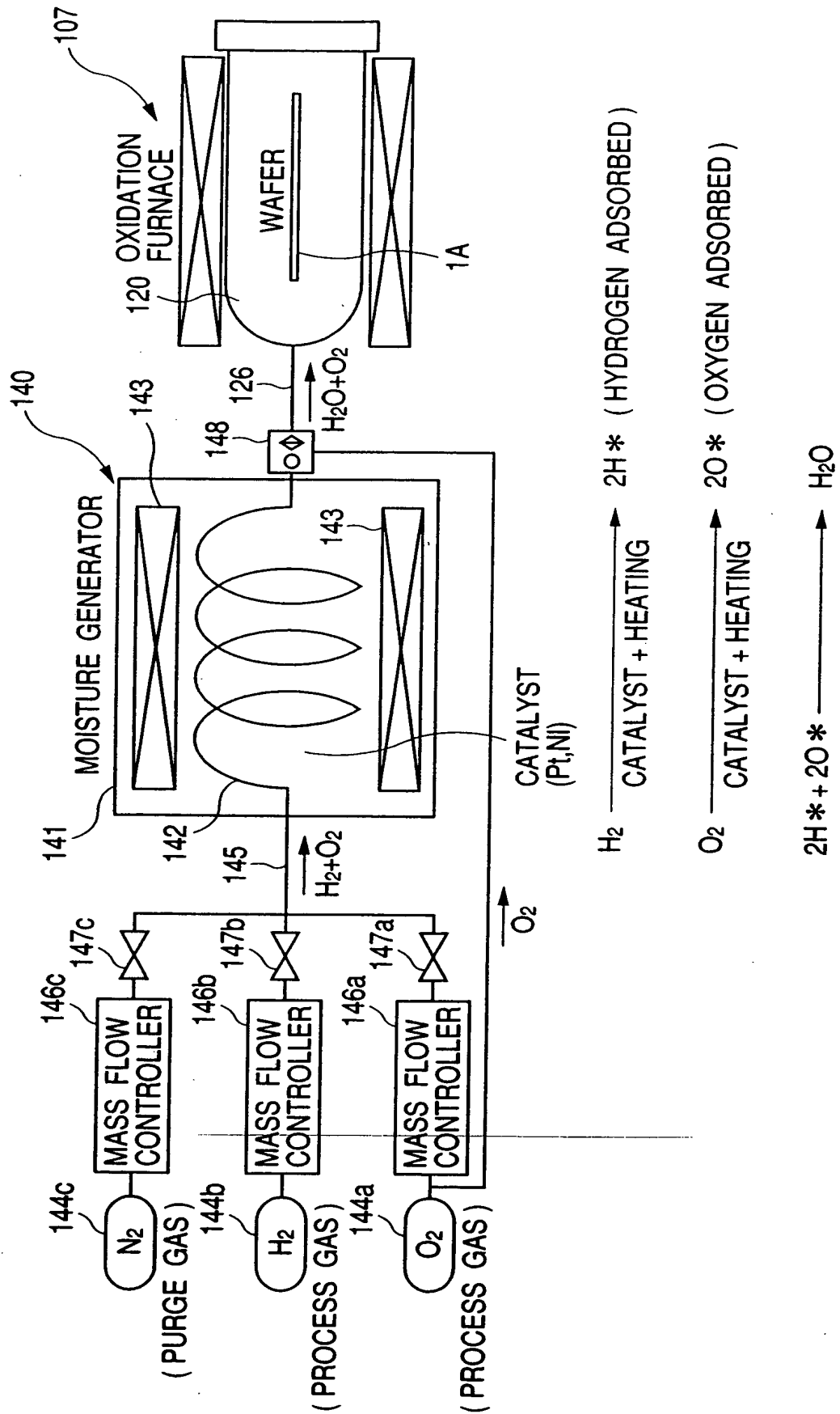


FIG. 14

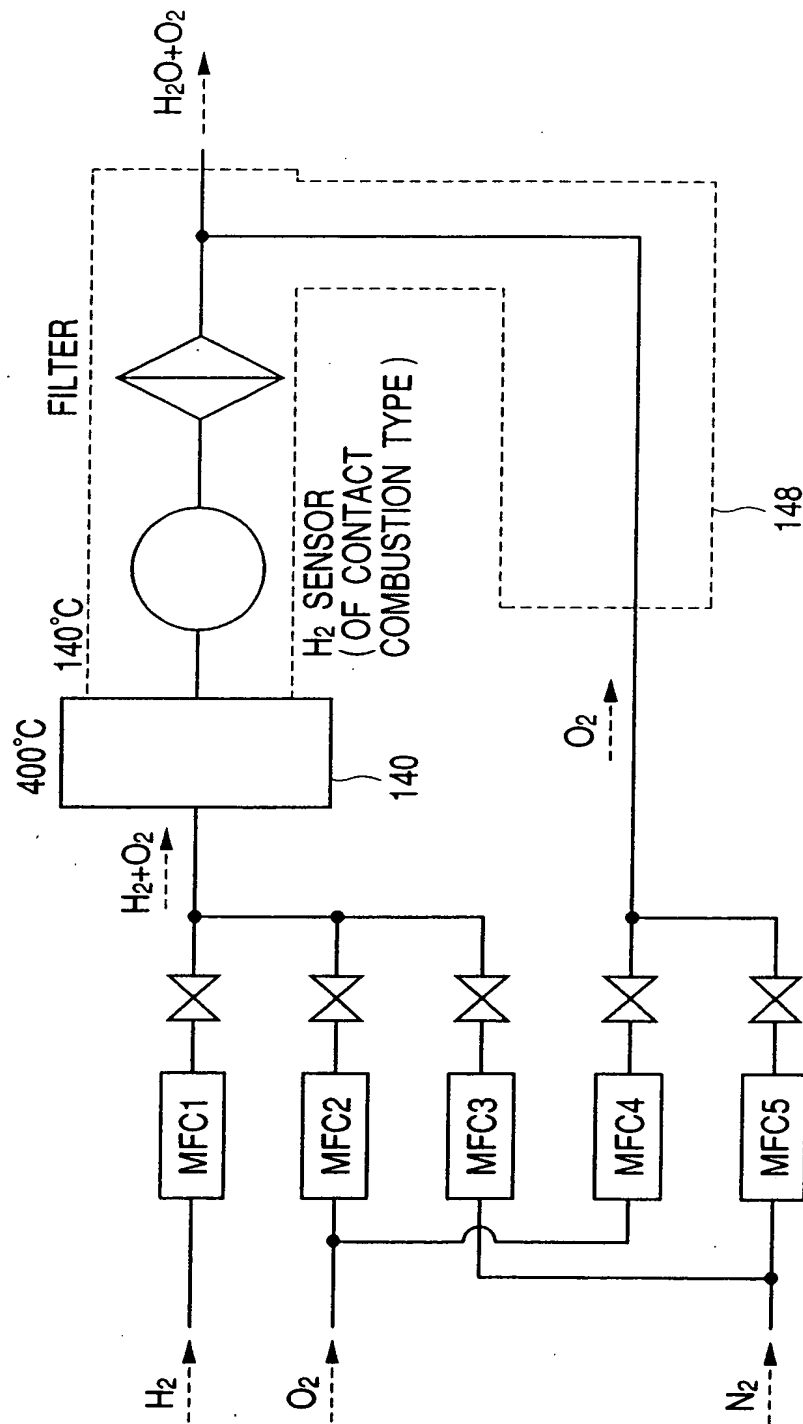
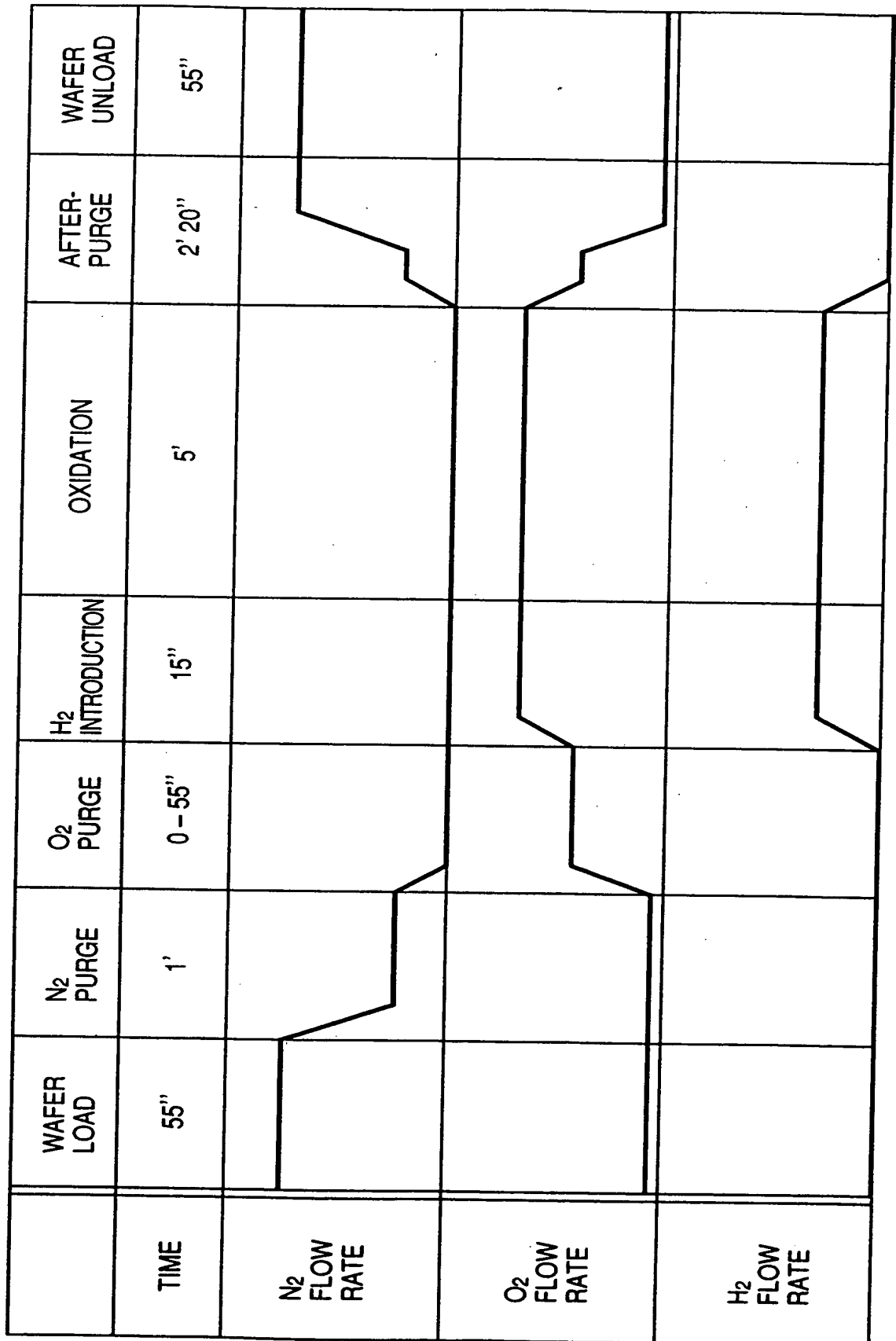


FIG. 15



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FIG. 16

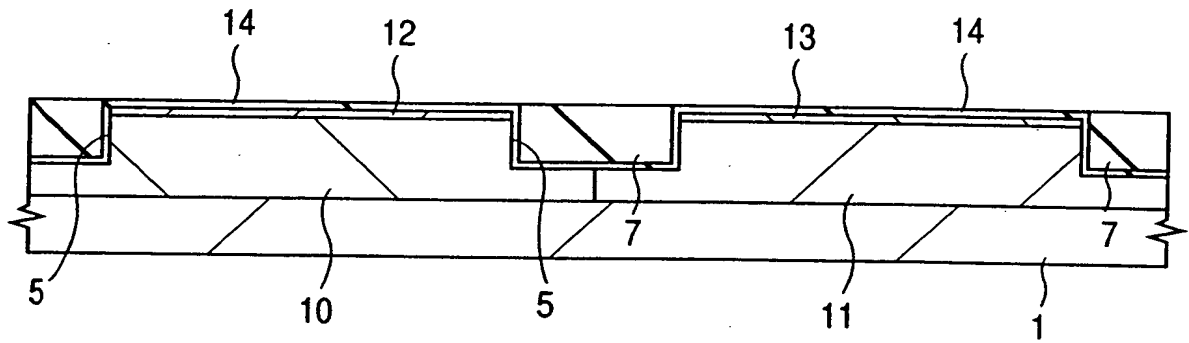


FIG. 17

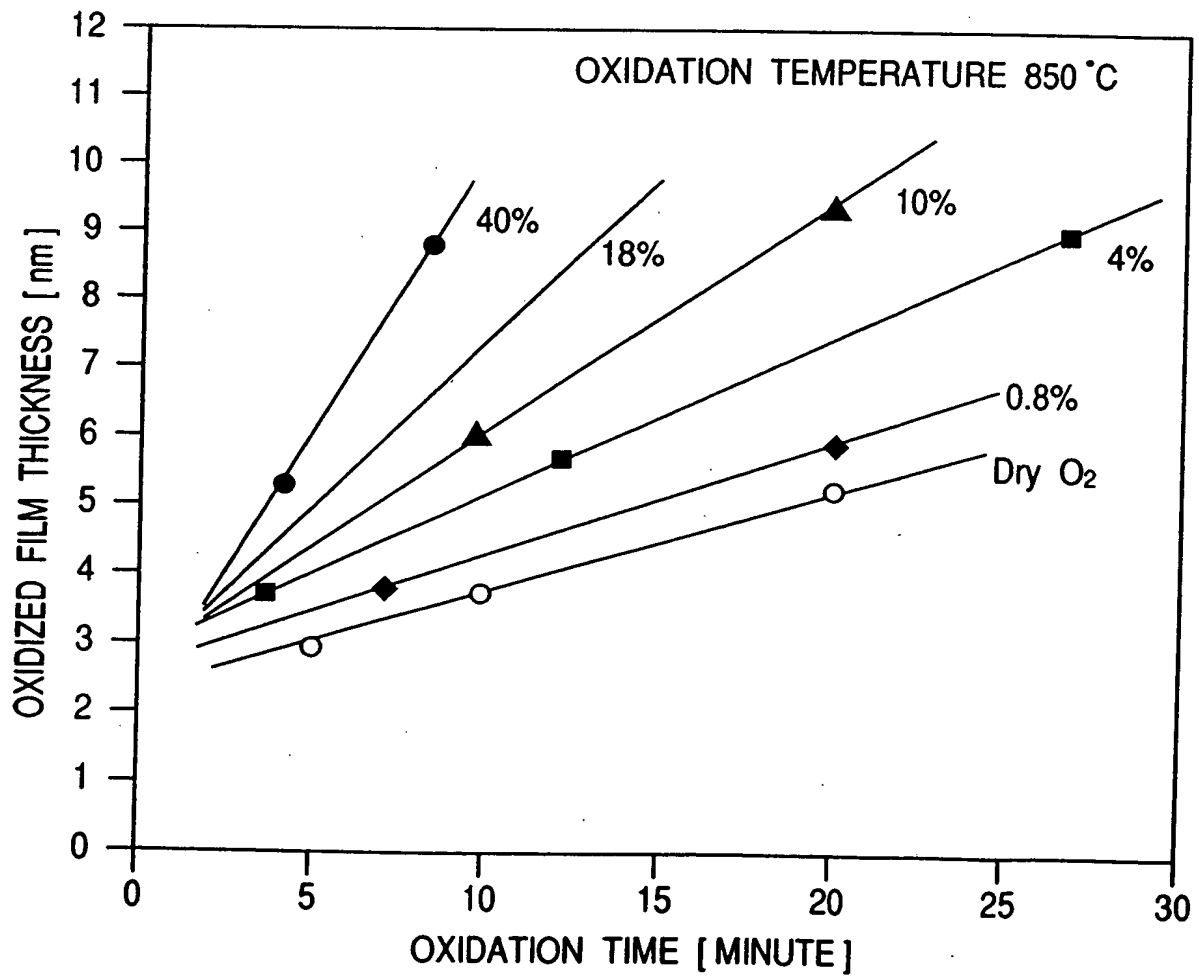
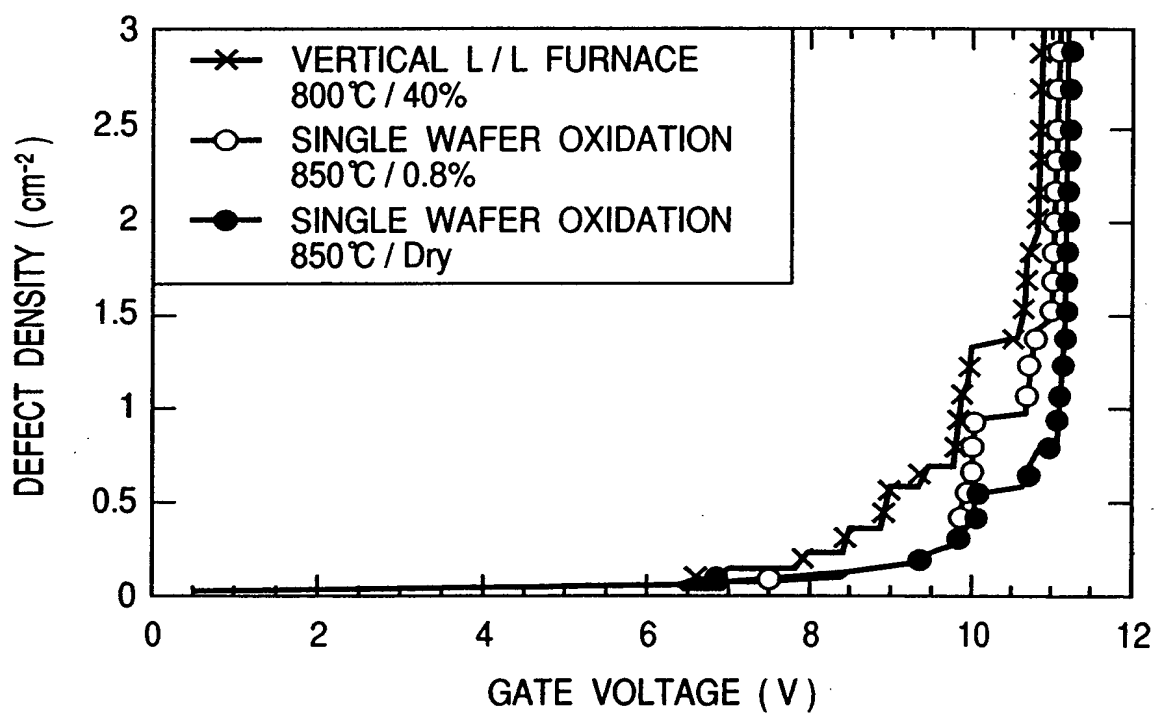
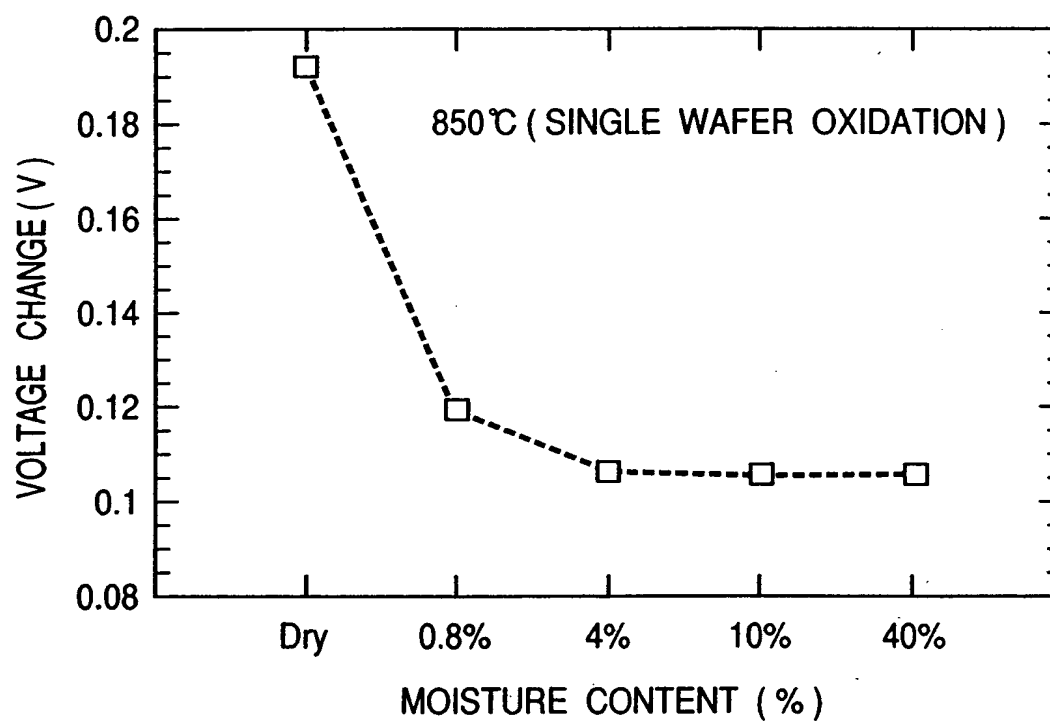


FIG. 18

INITIAL WITHSTAND VOLTAGE OF LOW MOISTURE
CONTENT OXIDE FILM
(OXIDE FILM THICKNESS = 9nm, $S = 0.19\text{cm}^2$)

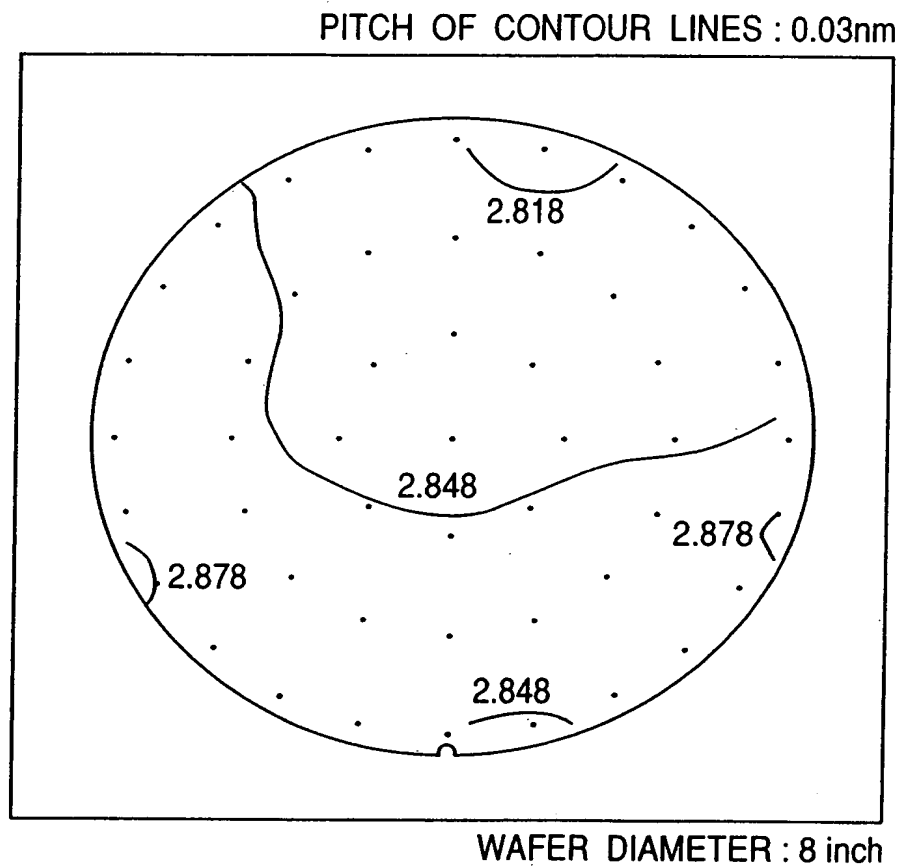
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FIG. 19



OXIDATION CONDITION DEPENDENCY
OF VOLTAGE CHANGE

FIG. 20



AVERAGE : 2.848 [nm]

MAX. : 2.881 [nm]

MIN. : 2.814 [nm]

MAX. - MIN. : 0.067 [nm]

± 1.18 [%]

TREATING CONDITIONS : 850°C, 2'30"

H₂ / O₂ : 0.05 / 4.9slm (MOISTURE CONTENT : 0.8%)

MEASUREMENT : AT 49 POINTS BY ELLIPSOMETER

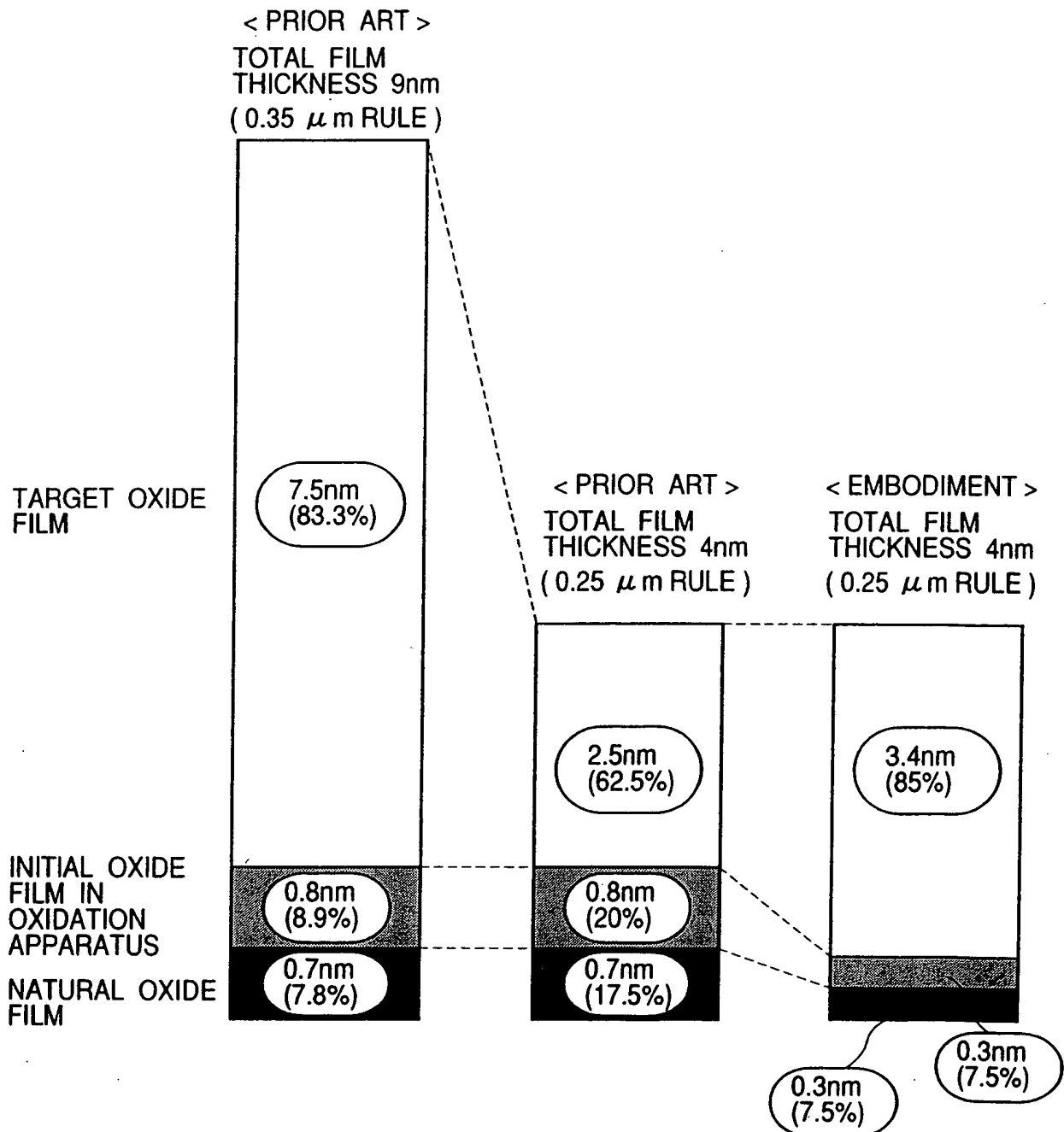
FIG. 21

FIG. 22

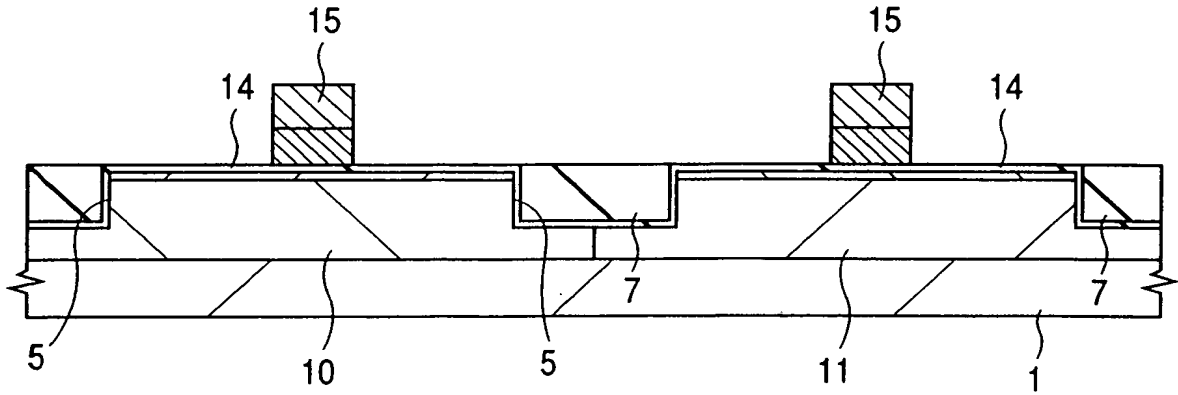


FIG. 23

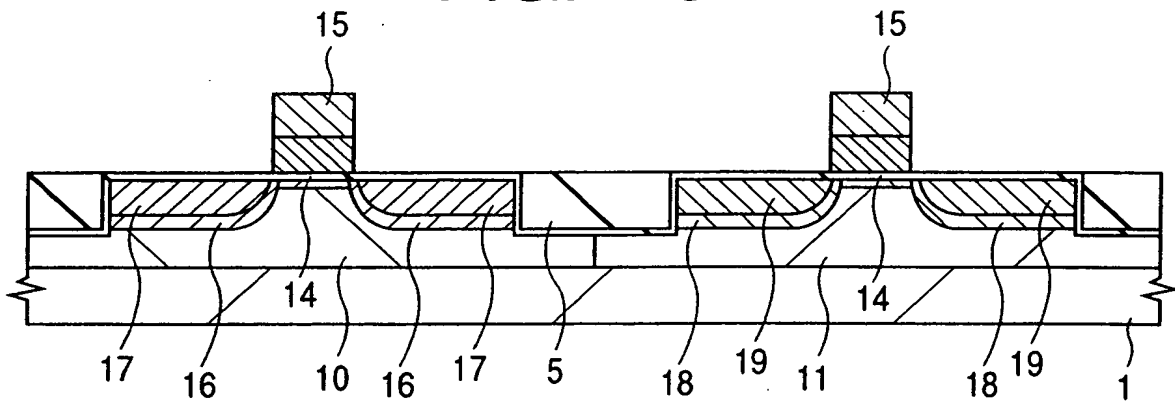


FIG. 24

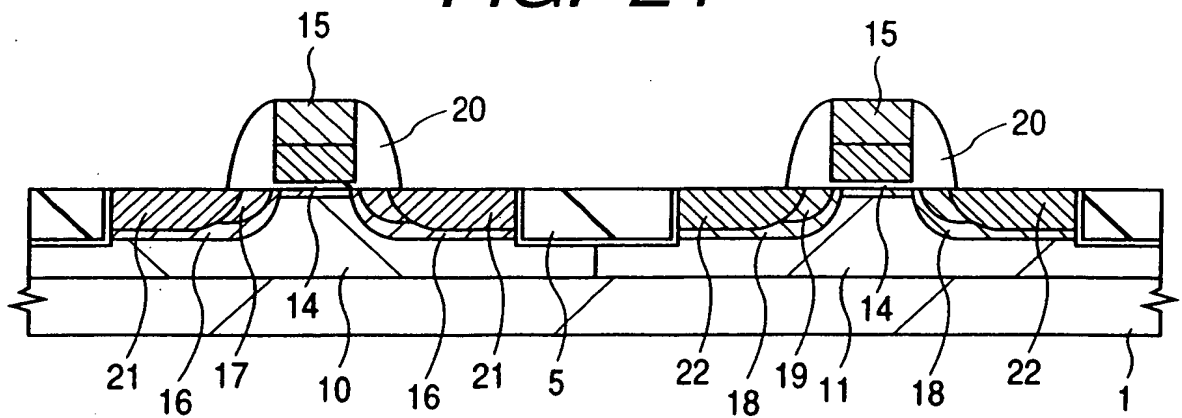


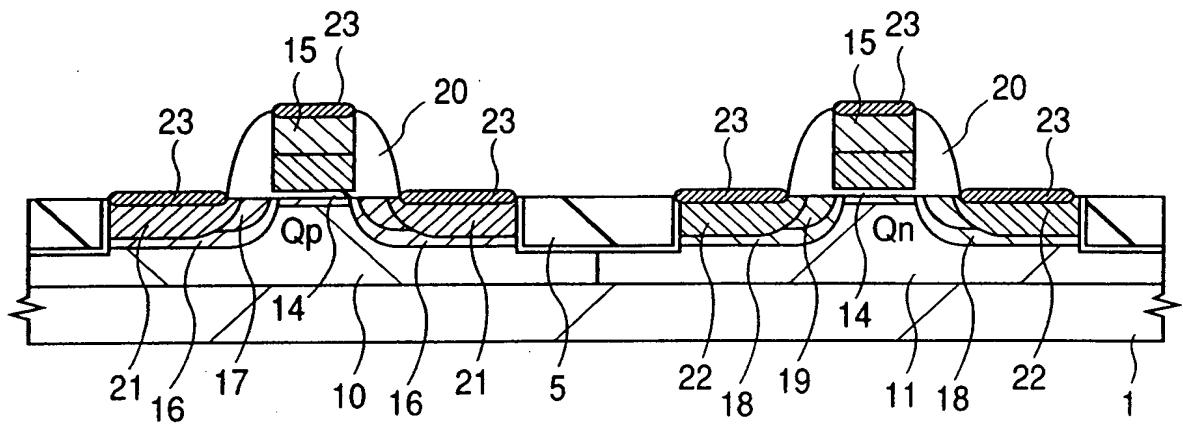
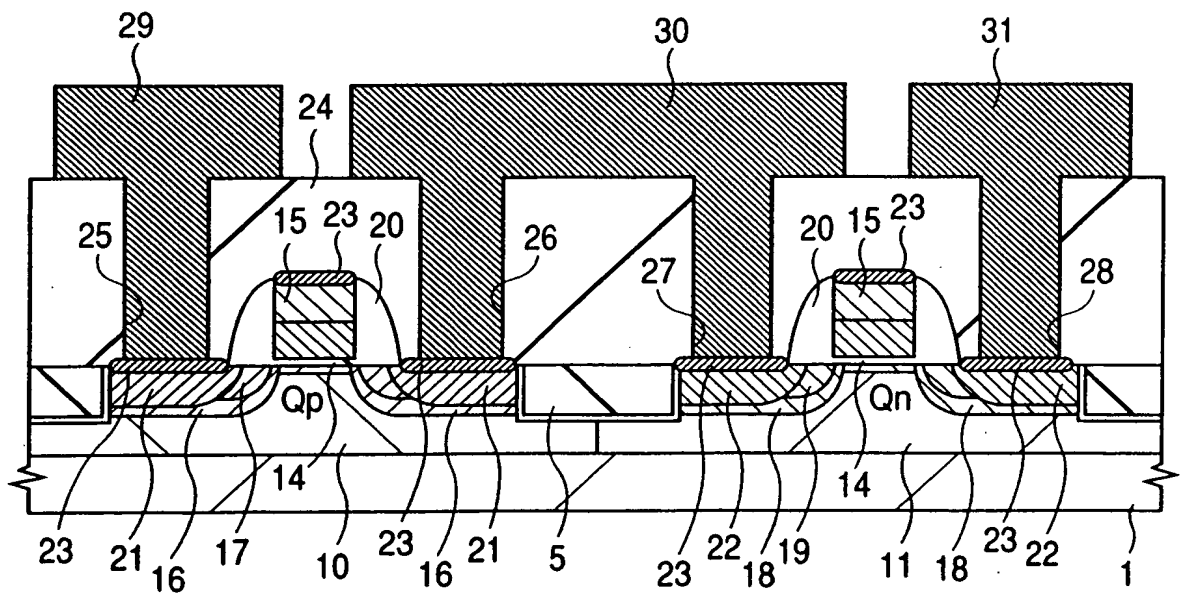
FIG. 25*FIG. 26*

FIG. 27

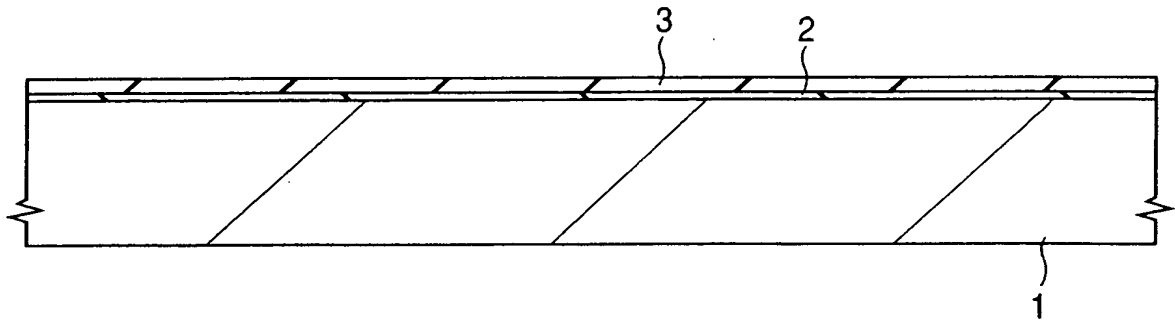


FIG. 28

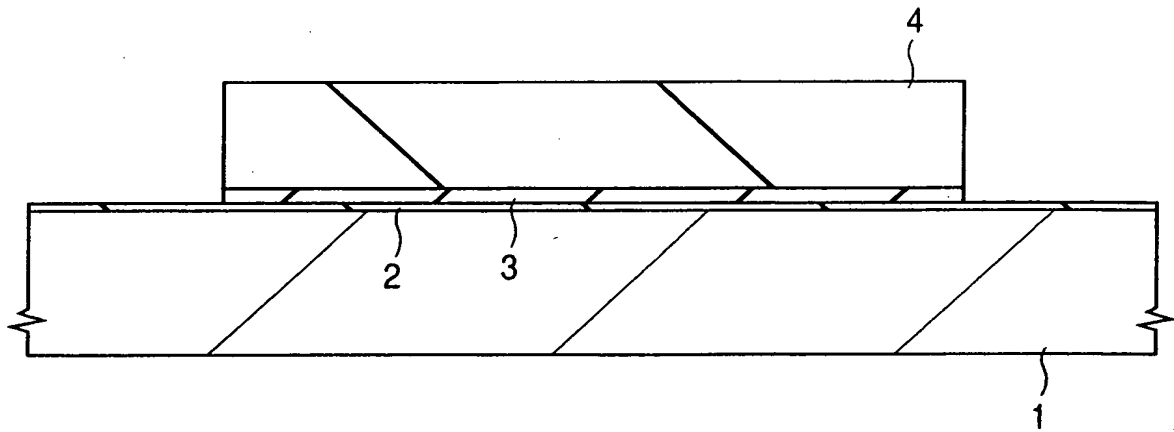


FIG. 29

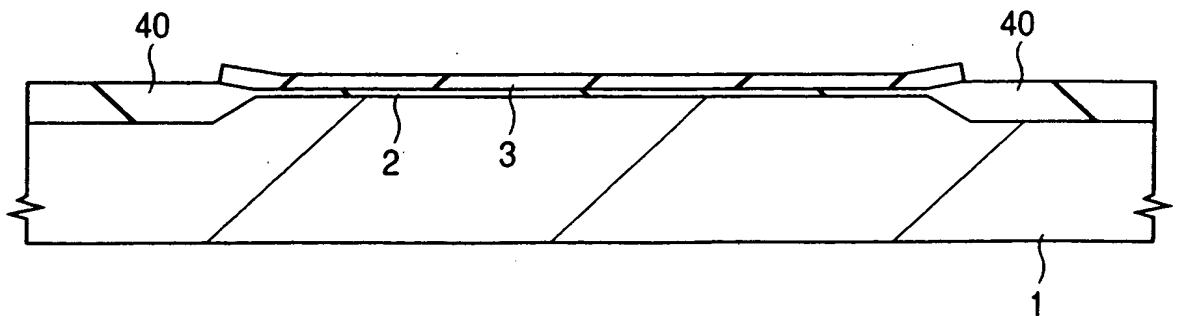


FIG. 30

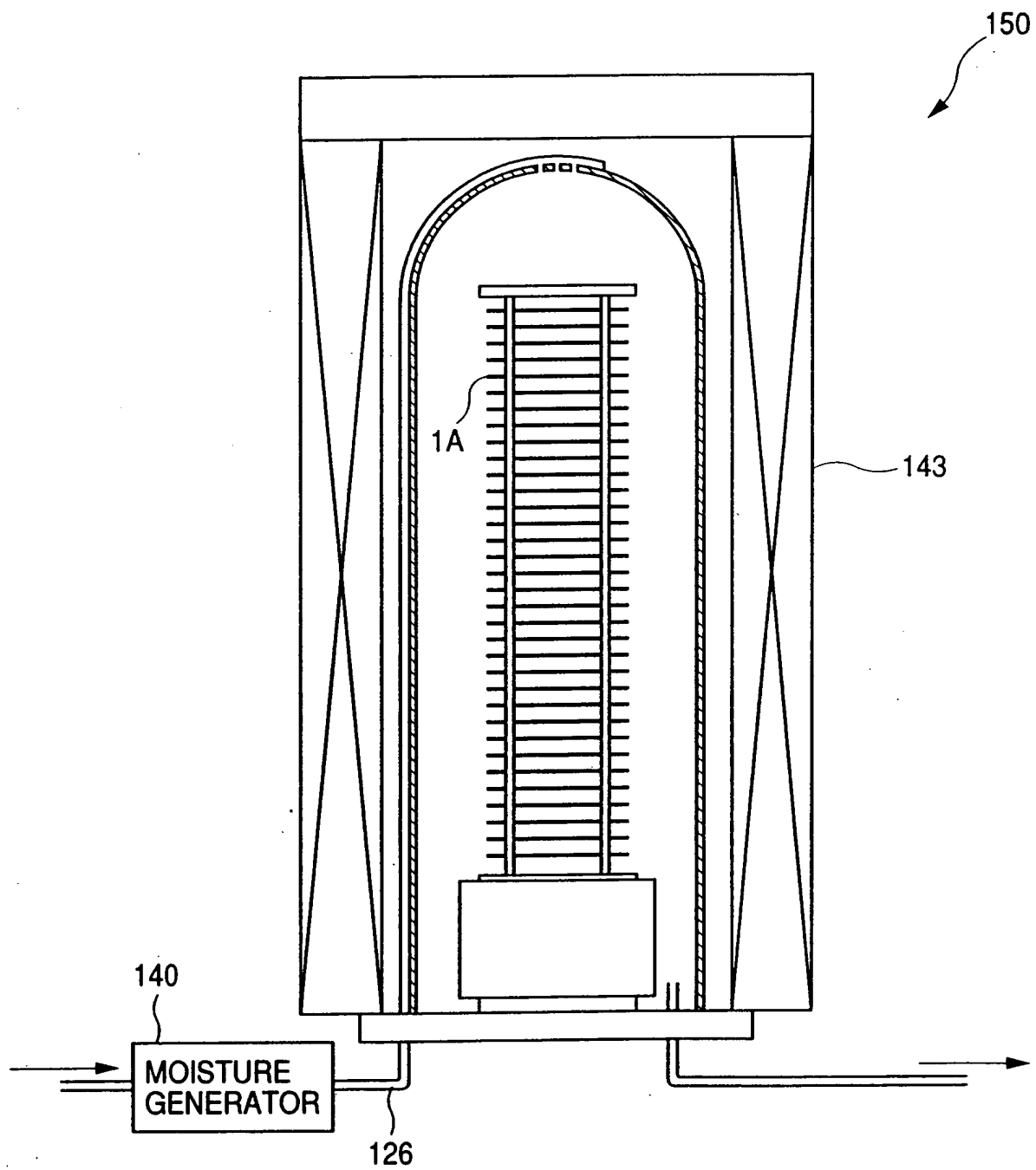


FIG. 31

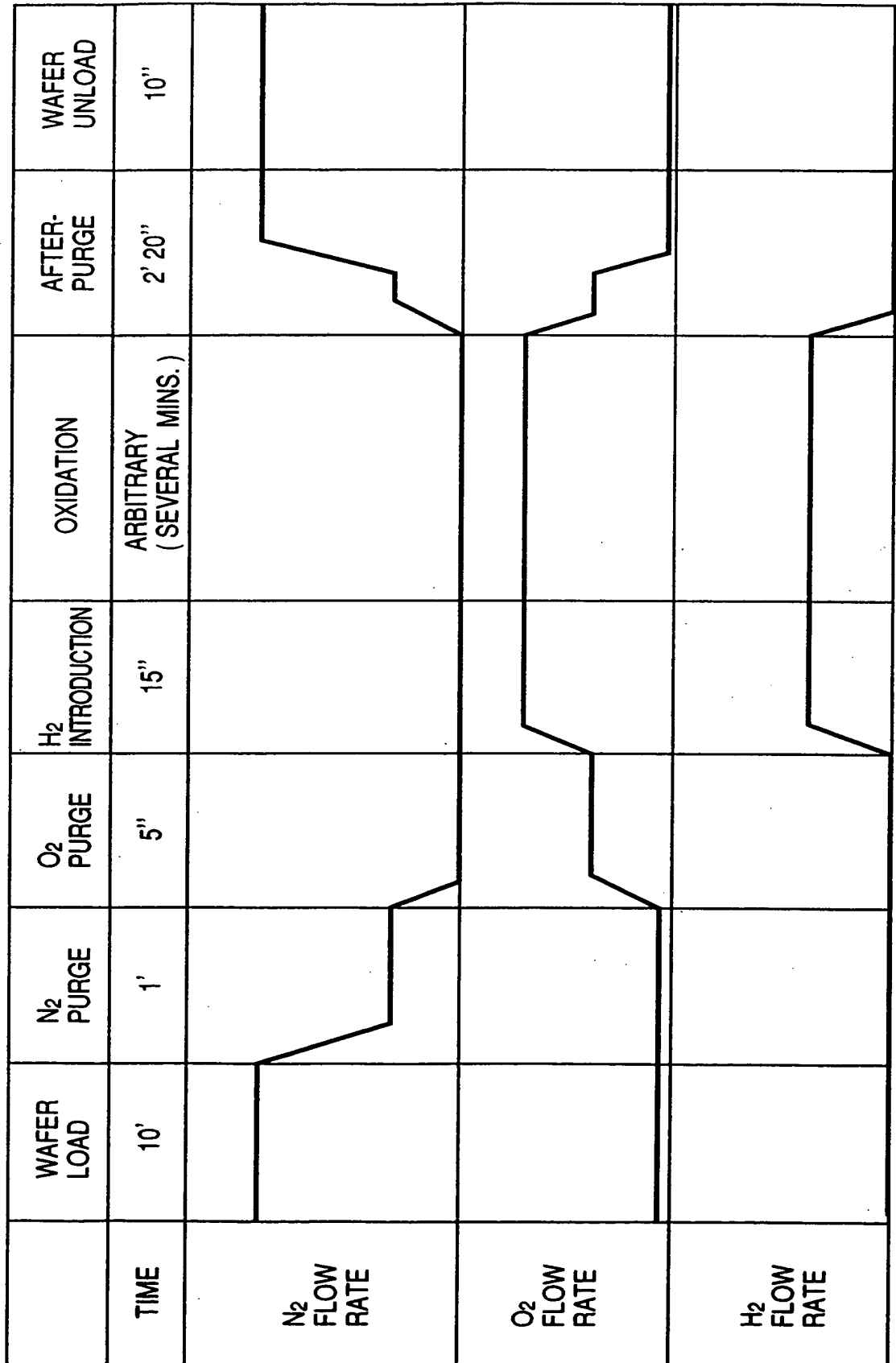


FIG. 32

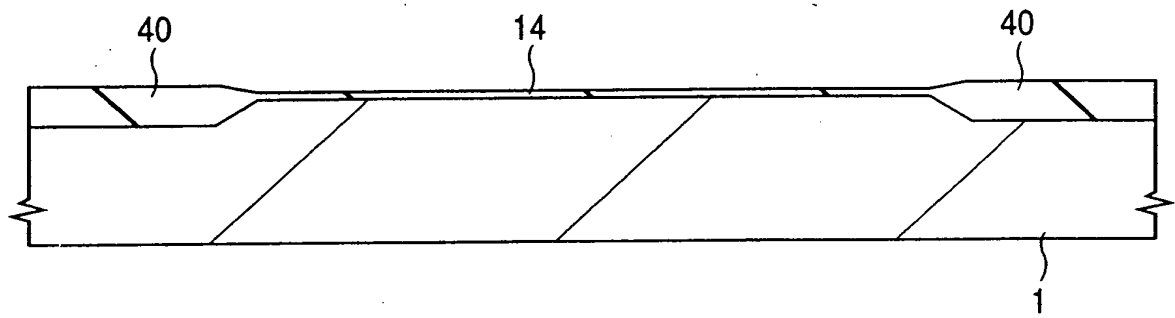


FIG. 34

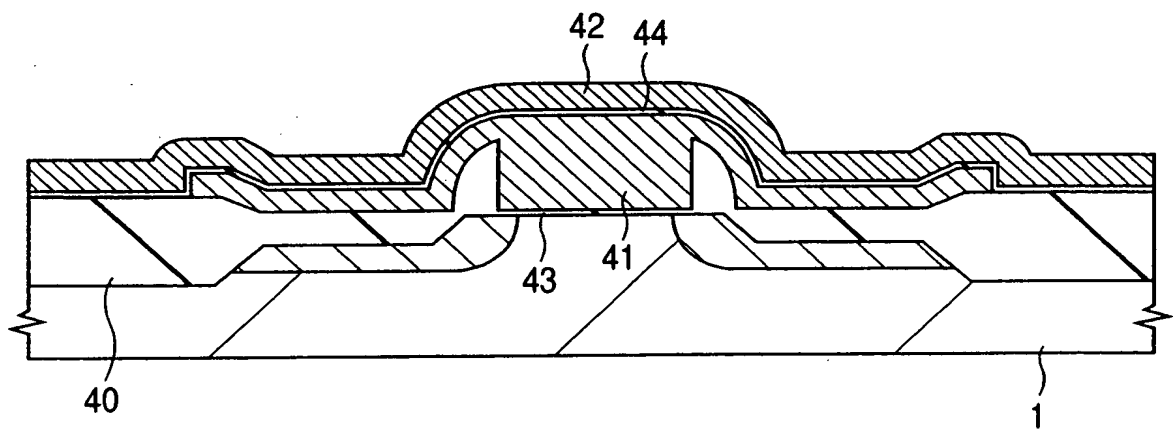


FIG. 33

